

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TANIMOTO, HIROYOSHI	
		Examiner Mary C Hogan	Art Unit 2123	Page 1 of 1

**U.S. PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	Hurkx et al, "A New Analytical Diode Model Including Tunneling and Avalanche Breakdown", IEEE Transactions on Electron Devices, Vol. 39, No. 9, September 1992		
V	Hurkx et al, "A New Recombination Model for Device Simulation Including Tunneling", IEEE Transactions on Electron Devices, Vol. 93, No. 2, February 1992.		
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